ON Semiconductor



FINAL PRODUCT/PROCESS CHANGE NOTIFICATION Generic Copy

15 Jul 2008

SUBJECT: ON Semiconductor Final Product/Process Change Notification #16133

TITLE: Dual Source ISMF Wafer Fab Qualification for Zener Products

PROPOSED FIRST SHIP DATE: 15 Oct 2008

AFFECTED CHANGE CATEGORY(S): ON Semiconductor Fab Site

AFFECTED PRODUCT DIVISION(S): Discrete Products Division

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION: Contact your local ON Semiconductor Sales Office or Kok Kheong Lim <<u>ffwffn@onsemi.com</u>>

SAMPLES: Contact your local ON Semiconductor Sales Office

ADDITIONAL RELIABILITY DATA: Available

Contact your local ON Semiconductor Sales Office or Laura Rivers <a>laura.rivers@onsemi.com>

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact your local ON Semiconductor Sales Office.

DESCRIPTION AND PURPOSE:

This is the Final notification announcing that ON Semiconductor is adding wafer fabrication capacity for the Zener/TVS products listed herein at the ISMF wafer fab in Seremban, Malaysia. The ISMF facility is an ON Semiconductor owned wafer fab that has been producing products for ON Semiconductor since 1998. Several existing technologies within ON Semiconductor's product families are currently sourced from ISMF, including Zener Diodes, Small Signal, and USB array filter products.

Quality and performance will be equal to current products. Electrical performance, datasheets and package dimensions will not change.

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RELIABILITY DATA SUMMARY:

Reliability Test Results:

Test	Conditions	Results
PreConditioning	MSL 1 @ 260C	0/240
Temp Cycle + PC	Ta= - 65 to 150C 1000 cycles	0/240
HTRB	Ta= 150C, Vbr=25V, 1008 hrs	0/240
HTSL	Ta= 150C, 1008 hours	0/240

ELECTRICAL CHARACTERISTIC SUMMARY:

Characterization summary of qual(ISMF) and control(Z/R) lots. 1) DC electrical parametric test(Vbr,IR and Vf)at -55C, 25C and 150C: Found no-significant difference and well within all spec limits for both groups. 2) ESD Rating: Compliance to IEC61000-4-2 15kV(air) and 8kV(contact) for both groups.

CHANGED PART IDENTIFICATION:

Product with a date code of 0842 (or NP or X) or later may be sourced from the ISMF facility.

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AFFECTED DEVICE LIST

NUP4201MR6T1 NUP4201MR6T1G SMS05CT1 SMS05CT1G SMS12CT1 SMS12CT1G SMS15CT1 SMS15CT1G SMS24CT1 SMS24CT1G LC03-6R2 LC03-6R2G NUP4201DR2 NUP4201DR2G SRDA05-4R2 SRDA05-4R2G SMF05CT1 SMF05CT1G SMF05CT2 SMF05CT2G SMF12CT1 SMF12CT1G SMF15CT1 SMF15CT1G SMF24CT1 SMF24CT1G NUP5120X6T1 NUP5120X6T1G NUP5120X6T2 NUP5120X6T2G NUP5150MUTBG